Scattering Parameter Characterization of Microwave Optoelectronic Devices and Fiber-Optic Networks

S. Iezekiel, C.M. Snowden and M.J. Howes. "Scattering Parameter Characterization of Microwave Optoelectronic Devices and Fiber-Optic Networks." 1991 Microwave and Guided Wave Letters 1.9 (Sep. 1991 [MGWL]): 233-235.

A microwave fiber-optic network analyzer test set is proposed that will allow the application of two-port calibration theory to the measurement of optical and optoelectronic components in high frequency fiber-optic links. Formulae for the optoelectronic calibration are presented, and a unified approach to optical and optoelectronic two-port calibration theory is covered.

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